Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/064,042	TSENG ET AL.	
Examiner	Art Unit	
V Paul Harner	2626	

SEARCHED			
Class	Subclass	Date	Examiner
704	205 212 203	2/10/2006	VPH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
East, EIC searches (attached), Google search, Inventor	2/10/2006	VPH
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